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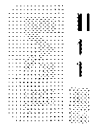new one in the text box.

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[Abstract]   [PDF Full-Text (196 KB)]   **IEEE JNL**

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Bangura, J.F.; Povinelli, R.J.; Demerdash, N.A.O.; Brown, R.H.;
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3 **Morphological profiles used for classification of data from urban are**
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[Abstract]   [PDF Full-Text (432 KB)]   **IEEE CNF**